



# 16-/32- Channel, 3.5 $\Omega$ 1.8 V to 5.5 V, $\pm 2.5$ V, Analog Multiplexers

## Preliminary Technical Data

## ADG726/ADG732

### FEATURES

**1.8 V to 5.5 V Single Supply**  
 **$\pm 2.5$  V Dual Supply Operation**  
**3.5  $\Omega$  On Resistance**  
**0.5  $\Omega$  On Resistance Flatness**  
**Rail to Rail Operation**  
**30ns Switching Times**  
**Single 32 to 1 Channel Multiplexer**  
**Dual/Differential 16 to 1 Channel Multiplexer**  
**TTL/CMOS Compatible Inputs**  
**For Functionally Equivalent devices with Serial Interface**  
**See ADG725/ADG731**

### APPLICATIONS

**Optical Applications**  
**Data Acquisition Systems**  
**Communication Systems**  
**Relay replacement**  
**Audio and Video Switching**  
**Battery Powered Systems**  
**Medical Instrumentation**  
**Automatic Test Equipment**

### GENERAL DESCRIPTION

The ADG726/ADG732 are monolithic CMOS 32 channel/dual 16 channel analog multiplexers. The ADG732 switches one of thirty-two inputs (S1-S32) to a common output, D, as determined by the 5-bit binary address lines A0, A1, A2, A3 and A4. The ADG726 switches one of sixteen inputs as determined by the four bit binary address lines, A0, A1, A2 and A3.

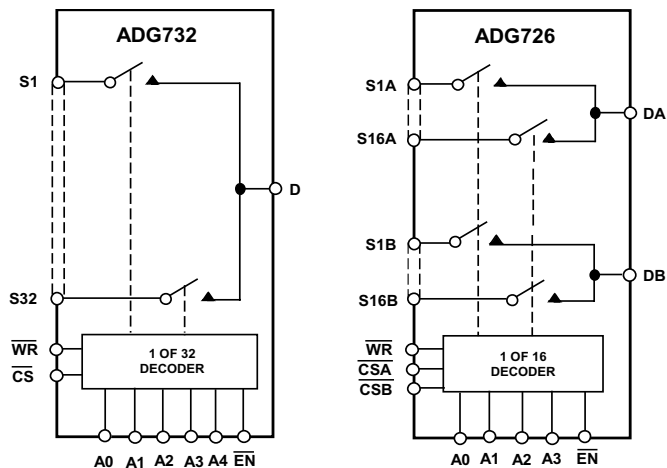
On chip latches facilitate microprocessor interfacing. The ADG726 device may also be configured for differential operation by tying CSA and CSB together. An  $\overline{\text{EN}}$  input is used to enable or disable the devices. When disabled, all channels are switched OFF.

These multiplexers are designed on an enhanced submicron process that provides low power dissipation yet gives high switching speed, very low on resistance and leakage currents. They operate from single supply of 1.8V to 5.5V and  $\pm 2.5$  V dual supply, making them ideally suited to a variety of applications. On resistance is in the region of a few Ohms and is closely matched between switches and very flat over the full signal range. These parts can operate equally well as either Multiplexers or De-Multiplexers

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### FUNCTIONAL BLOCK DIAGRAMS



and have an input signal range which extends to the supplies. In the OFF condition, signal levels up to the supplies are blocked. All channels exhibit break before make switching action preventing momentary shorting when switching channels.

They are available in either 48 lead LFCSP or TQFP package.

### PRODUCT HIGHLIGHTS

1. +1.8 V to +5.5 V Single or  $\pm 2.5$  V Dual Supply operation. These parts are specified and guaranteed with +5 V  $\pm 10\%$ , +3 V  $\pm 10\%$  single supply and  $\pm 2.5$  V  $\pm 10\%$  dual supply rails.
2. On Resistance of 3.5  $\Omega$ .
3. Guaranteed Break-Before-Make Switching Action.
4. 7mm x 7mm 48 lead LF Chip Scale Package (CSP) or 48 lead TQFP package.

# PRELIMINARY TECHNICAL DATA

## ADG726/ADG732—SPECIFICATIONS<sup>1</sup> ( $V_{DD} = 5V \pm 10\%$ , $V_{SS} = 0V$ , $GND = 0V$ , unless otherwise noted)

Parameter	B Version		Units	Test Conditions/Comments
	+25°C	-40°C to +85°C		
<b>ANALOG SWITCH</b>				
Analog Signal Range		0 V to $V_{DD}$	V	
On-Resistance ( $R_{ON}$ )	3.5	6	$\Omega$ typ $\Omega$ max	$V_S = 0V$ to $V_{DD}$ , $I_{DS} = 10\text{ mA}$ ; Test Circuit 1
On-Resistance Match Between Channels ( $\Delta R_{ON}$ )		0.3	$\Omega$ typ	$V_S = 0V$ to $V_{DD}$ , $I_{DS} = 10\text{ mA}$
On-Resistance Flatness ( $R_{FLAT(ON)}$ )	0.5	0.8	$\Omega$ max $\Omega$ typ $\Omega$ max	$V_S = 0V$ to $V_{DD}$ , $I_{DS} = 10\text{ mA}$
		1.2	$\Omega$ max	
<b>LEAKAGE CURRENTS</b>				
Source OFF Leakage $I_S$ (OFF)	$\pm 0.01$		nA typ	$V_{DD} = 5.5V$ $V_D = 4.5V/1V$ , $V_S = 1V/4.5V$ ; Test Circuit 2
	$\pm 0.5$	$\pm 5$	nA max	
Drain OFF Leakage $I_D$ (OFF)	$\pm 0.01$		nA typ	$V_D = 4.5V/1V$ , $V_S = 1V/4.5V$ ; Test Circuit 3
	$\pm 0.5$	$\pm 5$	nA max	
Channel ON Leakage $I_D$ , $I_S$ (ON)	$\pm 0.01$		nA typ	$V_D = V_S = 1V$ , or $4.5V$ ; Test Circuit 4
	$\pm 1$	$\pm 10$	nA max	
<b>DIGITAL INPUTS</b>				
Input High Voltage, $V_{INH}$		2.4	V min	
Input Low Voltage, $V_{INL}$		0.8	V max	
Input Current $I_{INL}$ or $I_{INH}$	0.005		$\mu\text{A}$ typ $\mu\text{A}$ max	$V_{IN} = V_{INL}$ or $V_{INH}$
		$\pm 0.1$	pF typ	
$C_{IN}$ , Digital Input Capacitance	5			
<b>DYNAMIC CHARACTERISTICS<sup>2</sup></b>				
$t_{TRANSITION}$	40	60	ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ , Test Circuit 5; $V_{S1} = 3V/0V$ , $V_{S32} = 0V/3V$
Break-Before-Make Time Delay, $t_D$	30	1	ns typ ns min	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ ; $V_S = 3V$ , Test Circuit 6
$t_{ON}(EN, \overline{WR})$	32	50	ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ ; $V_S = 3V$ , Test Circuit 7
$t_{OFF}(EN)$	10	14	ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ ; $V_S = 3V$ , Test Circuit 8
Charge Injection	$\pm 5$		pC typ	$V_S = 0V$ , $R_S = 0\ \Omega$ , $C_L = 1\text{ nF}$ ; Test Circuit 9
Off Isolation	-60		dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 100\text{ kHz}$ ; Test Circuit 10
Channel to Channel Crosstalk	-60		dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 100\text{ kHz}$ ; Test Circuit 11
-3 dB Bandwidth	10		MHz typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , Test Circuit 10
$C_S$ (OFF)	13		pF typ	$f = 1\text{ MHz}$
$C_D$ (OFF)				
ADG726	180		pF typ	$f = 1\text{ MHz}$
ADG732	360		pF typ	$f = 1\text{ MHz}$
$C_D$ , $C_S$ (ON)				
ADG726	200		pF typ	$f = 1\text{ MHz}$
ADG732	400		pF typ	$f = 1\text{ MHz}$
<b>POWER REQUIREMENTS</b>				
$I_{DD}$	10	20	$\mu\text{A}$ typ $\mu\text{A}$ max	$V_{DD} = +5.5V$ Digital Inputs = 0V or +5.5V

### NOTES

<sup>1</sup>Temperature range is as follows: B Version: -40°C to +85°C.

<sup>2</sup>Guaranteed by design, not subject to production test.

Specifications subject to change without notice.

# SPECIFICATIONS<sup>1</sup> ( $V_{DD} = 3V \pm 10\%$ , $V_{SS} = 0V$ , $GND = 0V$ , unless otherwise noted)

Parameter	B Version		Units	Test Conditions/Comments
	+25°C	-40°C to +85°C		
<b>ANALOG SWITCH</b>				
Analog Signal Range		0 V to $V_{DD}$	V	
On-Resistance ( $R_{ON}$ )	6		$\Omega$ typ	$V_S = 0V$ to $V_{DD}$ , $I_{DS} = 10$ mA;
	11	12	$\Omega$ max	Test Circuit 1
On-Resistance Match Between Channels ( $\Delta R_{ON}$ )		0.4	$\Omega$ typ	$V_S = 0V$ to $V_{DD}$ , $I_{DS} = 10$ mA
On-Resistance Flatness ( $R_{FLAT(ON)}$ )		1.2	$\Omega$ max	
		3	$\Omega$ max	$V_S = 0V$ to $V_{DD}$ , $I_{DS} = 10$ mA
<b>LEAKAGE CURRENTS</b>				
Source OFF Leakage $I_S$ (OFF)	$\pm 0.01$		nA typ	$V_{DD} = 3.3V$
	$\pm 1$	$\pm 5$	nA max	$V_S = 3V/1V$ , $V_D = 1V/3V$ ;
Drain OFF Leakage $I_D$ (OFF)	$\pm 0.01$		nA typ	Test Circuit 2
	$\pm 1$	$\pm 5$	nA max	$V_S = 1V/3V$ , $V_D = 3V/1V$ ;
Channel ON Leakage $I_D$ , $I_S$ (ON)	$\pm 0.01$		nA typ	Test Circuit 3
	$\pm 1$	$\pm 10$	nA max	$V_S = V_D = +1V$ or $+3V$ ;
				Test Circuit 4
<b>DIGITAL INPUTS</b>				
Input High Voltage, $V_{INH}$		2.0	V min	
Input Low Voltage, $V_{INL}$		0.8	V max	
Input Current				
$I_{INL}$ or $I_{INH}$	0.005		$\mu A$ typ	$V_{IN} = V_{INL}$ or $V_{INH}$
		$\pm 0.1$	$\mu A$ max	
$C_{IN}$ , Digital Input Capacitance	5		pF typ	
<b>DYNAMIC CHARACTERISTICS<sup>2</sup></b>				
$t_{TRANSITION}$	45		ns typ	$R_L = 300\Omega$ , $C_L = 35$ pF Test Circuit 5
		75	ns max	$V_{S1} = 2V/0V$ , $V_{S32} = 0V/2V$
Break-Before-Make Time Delay, $t_D$	30		ns typ	$R_L = 300\Omega$ , $C_L = 35$ pF;
		1	ns min	$V_S = 2V$ , Test Circuit 6
$t_{ON}(EN, \overline{WR})$	40		ns typ	$R_L = 300\Omega$ , $C_L = 35$ pF;
		70	ns max	$V_S = 2V$ , Test Circuit 7
$t_{OFF}(EN)$	20		ns typ	$R_L = 300\Omega$ , $C_L = 35$ pF;
		28	ns max	$V_S = 2V$ , Test Circuit 8
Charge Injection	$\pm 5$		pC typ	$V_S = 0V$ , $R_S = 0\Omega$ , $C_L = 1$ nF;
				Test Circuit 9
Off Isolation	-60		dB typ	$R_L = 50\Omega$ , $C_L = 5$ pF, $f = 1$ MHz;
				Test Circuit 10
Channel to Channel Crosstalk	-60		dB typ	$R_L = 50\Omega$ , $C_L = 5$ pF, $f = 1$ MHz;
				Test Circuit 11
-3 dB Bandwidth	10		MHz typ	$R_L = 50\Omega$ , $C_L = 5$ pF, Test Circuit 10
$C_S$ (OFF)	13		pF typ	$f = 1$ MHz
$C_D$ (OFF)				
ADG726	180		pF typ	$f = 1$ MHz
ADG732	360		pF typ	$f = 1$ MHz
$C_D$ , $C_S$ (ON)				
ADG726	200		pF typ	$f = 1$ MHz
ADG732	400		pF typ	$f = 1$ MHz
<b>POWER REQUIREMENTS</b>				
$I_{DD}$	10		$\mu A$ typ	$V_{DD} = +3.3V$
		20	$\mu A$ max	Digital Inputs = 0 V or +3.3 V

## NOTES

<sup>1</sup>Temperature ranges are as follows: B Version: -40°C to +85°C.<sup>2</sup>Guaranteed by design, not subject to production test.

Specifications subject to change without notice.

PRELIMINARY TECHNICAL DATA

# ADG726/ADG732—SPECIFICATIONS<sup>1</sup> Dual Supply

( $V_{DD} = +2.5\text{ V} \pm 10\%$ ,  $V_{SS} = -2.5\text{ V} \pm 10\%$ ,  $GND = 0\text{ V}$ , unless otherwise noted)

Parameter	B Version		Units	Test Conditions/Comments
	+25°C	-40°C to +85°C		
<b>ANALOG SWITCH</b>				
Analog Signal Range		$V_{SS}$ to $V_{DD}$	V	
On-Resistance ( $R_{ON}$ )	3.5		$\Omega$ typ	$V_S = V_{SS}$ to $V_{DD}$ , $I_{DS} = 10\text{ mA}$ ; Test Circuit 1
	5.5	6	$\Omega$ max	
On-Resistance Match Between Channels ( $\Delta R_{ON}$ )		0.3	$\Omega$ typ	$V_S = V_{SS}$ to $V_{DD}$ , $I_{DS} = 10\text{ mA}$
		0.8	$\Omega$ max	
On-Resistance Flatness ( $R_{FLAT(ON)}$ )	0.5		$\Omega$ typ	$V_S = V_{SS}$ to $V_{DD}$ , $I_{DS} = 10\text{ mA}$
		1.2	$\Omega$ max	
<b>LEAKAGE CURRENTS</b>				
Source OFF Leakage $I_S$ (OFF)	$\pm 0.01$		nA typ	$V_{DD} = +2.75\text{ V}$ , $V_{SS} = -2.75\text{ V}$ $V_S = +2.25\text{ V}/-1.25\text{ V}$ , $V_D = -1.25\text{ V}/+2.25\text{ V}$ ; Test Circuit 2
	$\pm 1$	$\pm 5$	nA max	
Drain OFF Leakage $I_D$ (OFF)	$\pm 0.01$		nA typ	$V_S = +2.25\text{ V}/-1.25\text{ V}$ , $V_D = -1.25\text{ V}/+2.25\text{ V}$ ; Test Circuit 3
	$\pm 1$	$\pm 5$	nA max	
Channel ON Leakage $I_D$ , $I_S$ (ON)	$\pm 0.01$		nA typ	$V_S = V_D = +2.25\text{ V}/-1.25\text{ V}$ , Test Circuit 4
	$\pm 1$	$\pm 10$	nA max	
<b>DIGITAL INPUTS</b>				
Input High Voltage, $V_{INH}$		1.7	V min	
Input Low Voltage, $V_{INL}$		0.7	V max	
Input Current $I_{INL}$ or $I_{INH}$	0.005		$\mu\text{A}$ typ	$V_{IN} = V_{INL}$ or $V_{INH}$
		$\pm 0.1$	$\mu\text{A}$ max	
$C_{IN}$ , Digital Input Capacitance	5		pF typ	
<b>DYNAMIC CHARACTERISTICS<sup>2</sup></b>				
$t_{TRANSITION}$	40		ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ Test Circuit 5
		60	ns max	$V_{S1} = 1.5\text{ V}/0\text{ V}$ , $V_{S32} = 0\text{ V}/1.5\text{ V}$
Break-Before-Make Time Delay, $t_D$	15		ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ ;
		1	ns min	$V_S = 1.5\text{ V}$ , Test Circuit 6
$t_{ON}(EN, \overline{WR})$	32		ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ ;
		50	ns max	$V_S = 1.5\text{ V}$ , Test Circuit 7
$t_{OFF}(EN)$	16		ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ ;
		26	ns max	$V_S = 1.5\text{ V}$ , Test Circuit 8
Charge Injection	$\pm 8$		pC typ	$V_S = 0\text{ V}$ , $R_S = 0\ \Omega$ , $C_L = 1\text{ nF}$ ; Test 9
Off Isolation	-60		dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; Test Circuit 10
Channel to Channel Crosstalk	-60		dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; Test Circuit 11
-3 dB Bandwidth	10		MHz typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , Test Circuit 10
$C_S$ (OFF)	13		pF typ	
$C_D$ (OFF)				
ADG726	180		pF typ	$f = 1\text{ MHz}$
ADG732	360		pF typ	$f = 1\text{ MHz}$
$C_D$ , $C_S$ (ON)				
ADG726	200		pF typ	$f = 1\text{ MHz}$
ADG732	400		pF typ	$f = 1\text{ MHz}$
<b>POWER REQUIREMENTS</b>				
$I_{DD}$	10		$\mu\text{A}$ typ	$V_{DD} = +2.75\text{ V}$ Digital Inputs = 0 V or +2.75 V
		20	$\mu\text{A}$ max	
$I_{SS}$	10		$\mu\text{A}$ typ	$V_{SS} = -2.75\text{ V}$ Digital Inputs = 0 V or +2.75 V
		20	$\mu\text{A}$ max	

NOTES

<sup>1</sup>Temperature range is as follows: B Version: -40°C to +85°C.

<sup>2</sup>Guaranteed by design, not subject to production test.

Specifications subject to change without notice.

**TIMING CHARACTERISTICS<sup>1,2,3</sup>**

Parameter	Limit at T <sub>MIN</sub> , T <sub>MAX</sub>	Units	Conditions/Comments
t <sub>1</sub>	0	ns min	$\overline{CS}$ to $\overline{WR}$ Setup Time
t <sub>2</sub>	0	ns min	$\overline{CS}$ to $\overline{WR}$ Hold Time
t <sub>3</sub>	20	ns min	$\overline{WR}$ pulse width
t <sub>4</sub>	10	ns min	Time between $\overline{WR}$ cycles
t <sub>5</sub>	5	ns min	Address, Enable Setup Time
t <sub>6</sub>	2	ns min	Address, Enable Hold Time

NOTES

<sup>1</sup>See Figure 1.

<sup>2</sup>All input signals are specified with tr = tf = 5ns (10% to 90% of V<sub>DD</sub>) and timed from a voltage level of (V<sub>IL</sub> + V<sub>IH</sub>)/2.

<sup>3</sup>Guaranteed by design and characterisation, not production tested.

Specifications subject to change without notice.

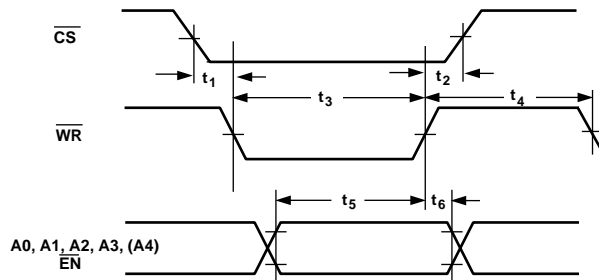


Figure 1. Timing Diagram

Figure 1 shows the timing sequence for latching the switch address and enable inputs. The latches are level sensitive; therefore, while  $\overline{WR}$  is held low, the latches are transparent and the switches respond to the address and enable inputs. This input data is latched on the rising edge of  $\overline{WR}$ . The ADG726 has two  $\overline{CS}$  inputs. This enables the part to be used either as a dual 16-1 channel multiplexer or a differential 16 channel multiplexer. If a differential output is required, tie  $\overline{CSA}$  and  $\overline{CSB}$  together.

# PRELIMINARY TECHNICAL DATA

## ADG726/ADG732

### ABSOLUTE MAXIMUM RATINGS<sup>1</sup>

(T<sub>A</sub> = +25°C unless otherwise noted)

V <sub>DD</sub> to V <sub>SS</sub>	+7 V
V <sub>DD</sub> to GND	-0.3 V to +7 V
V <sub>SS</sub> to GND	+0.3 V to -7 V
Analog Inputs <sup>2</sup>	V <sub>SS</sub> - 0.3 V to V <sub>DD</sub> +0.3 V or 30 mA, Whichever Occurs First
Digital Inputs <sup>2</sup>	-0.3V to V <sub>DD</sub> +0.3 V or 30 mA, Whichever Occurs First
Peak Current, S or D	60mA (Pulsed at 1 ms, 10% Duty Cycle max)
Continuous Current, S or D	30mA
Operating Temperature Range	
Industrial (B Version)	-40°C to +85°C

Storage Temperature Range	-65°C to +150°C
Junction Temperature	+150°C
48 lead CSP θ <sub>JA</sub> Thermal Impedance	TBD°C/W
48 lead TQFP θ <sub>JA</sub> Thermal Impedance	TBD°C/W
Lead Temperature, Soldering (10seconds)	300°C
IR Reflow, Peak Temperature	+220°C

### NOTES

<sup>1</sup>Stresses above those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

<sup>2</sup>Overvoltages at A,  $\overline{WR}$ ,  $\overline{RS}$ , S or D will be clamped by internal diodes. Current should be limited to the maximum ratings given.

### CAUTION

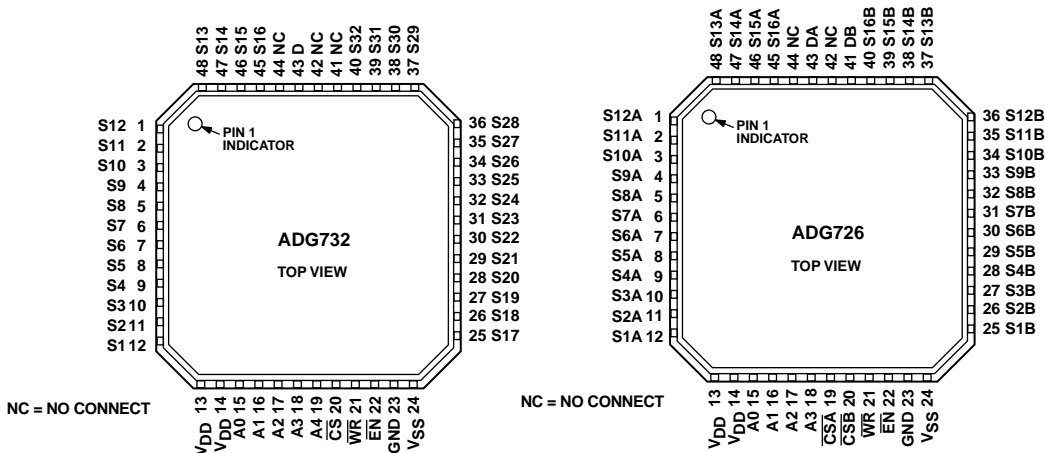
ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the ADG726/ADG732 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



### ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG726BCP	-40 °C to +85 °C	Chip Scale Package (CSP)	CP-48
ADG726BSU	-40 °C to +85 °C	Thin Quad Flatpack	SU-48
ADG732BCP	-40 °C to +85 °C	Chip Scale Package (CSP)	CP-48
ADG732BSU	-40 °C to +85 °C	Thin Quad Flatpack	SU-48

### PIN CONFIGURATIONS CSP & TQFP



# PRELIMINARY TECHNICAL DATA

## ADG726/ADG732

**Table 1. ADG726 Truth Table**

A3	A2	A1	A0	$\overline{E}\overline{N}$	$\overline{C}\overline{S}\overline{A}$	$\overline{C}\overline{S}\overline{B}$	$\overline{W}\overline{R}$	ON Switch
X	X	X	X	X	1	1	L->H	Retains previous switch condition
X	X	X	X	X	1	1	X	No Change in Switch condition
X	X	X	X	1	0	0	0	NONE
0	0	0	0	0	0	0	0	S1A - DA, S1B - DB
0	0	0	1	0	0	0	0	S2A - DA, S2B - DB
0	0	1	0	0	0	0	0	S3A - DA, S3B - DB
0	0	1	1	0	0	0	0	S4A - DA, S4B - DB
0	1	0	0	0	0	0	0	S5A - DA, S5B - DB
0	1	0	1	0	0	0	0	S6A - DA, S6B - DB
0	1	1	0	0	0	0	0	S7A - DA, S7B - DB
0	1	1	1	0	0	0	0	S8A - DA, S8B - DB
1	0	0	0	0	0	0	0	S9A - DA, S9B - DB
1	0	0	1	0	0	0	0	S10A - DA, S10B - DB
1	0	1	0	0	0	0	0	S11A - DA, S11B - DB
1	0	1	1	0	0	0	0	S12A - DA, S12B - DB
1	1	0	0	0	0	0	0	S13A - DA, S13B - DB
1	1	0	1	0	0	0	0	S14A - DA, S14B - DB
1	1	1	0	0	0	0	0	S15A - DA, S15B - DB
1	1	1	1	0	0	0	0	S16A - DA, S16B - DB

**Table 2. ADG732 Truth Table**

A4	A3	A2	A1	A0	$\overline{E}\overline{N}$	$\overline{C}\overline{S}$	$\overline{W}\overline{R}$	Switch Condition
X	X	X	X	X	X	1	L->H	Retains previous switch condition
X	X	X	X	X	X	1	X	No Change in Switch Condition
X	X	X	X	X	1	0	0	NONE
0	0	0	0	0	0	0	0	1
0	0	0	0	1	0	0	0	2
0	0	0	1	0	0	0	0	3
0	0	0	1	1	0	0	0	4
0	0	1	0	0	0	0	0	5
0	0	1	0	1	0	0	0	6
0	0	1	1	0	0	0	0	7
0	0	1	1	1	0	0	0	8
0	1	0	0	0	0	0	0	9
0	1	0	0	1	0	0	0	10
0	1	0	1	0	0	0	0	11
0	1	0	1	1	0	0	0	12
0	1	1	0	0	0	0	0	13
0	1	1	0	1	0	0	0	14
0	1	1	1	0	0	0	0	15
0	1	1	1	1	0	0	0	16
1	0	0	0	0	0	0	0	17
1	0	0	0	1	0	0	0	18
1	0	0	1	0	0	0	0	19
1	0	0	1	1	0	0	0	20
1	0	1	0	0	0	0	0	21
1	0	1	0	1	0	0	0	22
1	0	1	1	0	0	0	0	23
1	0	1	1	1	0	0	0	24
1	1	0	0	0	0	0	0	25
1	1	0	0	1	0	0	0	26
1	1	0	1	0	0	0	0	27
1	1	0	1	1	0	0	0	28
1	1	1	0	0	0	0	0	29
1	1	1	0	1	0	0	0	30
1	1	1	1	0	0	0	0	31
1	1	1	1	1	0	0	0	32

X = Don't Care  
REV. PrD

## ADG726/ADG732

## TERMINOLOGY

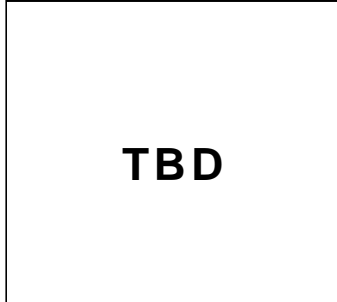
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$V_{DD}$	Most positive power supply potential.
$V_{SS}$	Most Negative power supply in a dual supply application. In single supply applications, connect to GND.
$I_{DD}$	Positive supply current.
$I_{SS}$	Negative supply current.
GND	Ground (0 V) reference.
S	Source terminal. May be an input or output.
D	Drain terminal. May be an input or output.
IN	Logic control input.
$V_D (V_S)$	Analog voltage on terminals D, S
$R_{ON}$	Ohmic resistance between D and S.
$\Delta R_{ON}$	On resistance match between any two channels, i.e. $R_{ONmax} - R_{ONmin}$
$R_{FLAT(ON)}$	Flatness is defined as the difference between the maximum and minimum value of on-resistance as measured over the specified analog signal range.
$I_S$ (OFF)	Source leakage current with the switch "OFF."
$I_D$ (OFF)	Drain leakage current with the switch "OFF."
$I_D, I_S$ (ON)	Channel leakage current with the switch "ON."
$V_{INL}$	Maximum input voltage for logic "0".
$V_{INH}$	Minimum input voltage for logic "1".
$I_{INL}(I_{INH})$	Input current of the digital input.
$C_S$ (OFF)	"OFF" switch source capacitance. Measured with reference to ground.
$C_D$ (OFF)	"OFF" switch drain capacitance. Measured with reference to ground.
$C_D, C_S$ (ON)	"ON" switch capacitance. Measured with reference to ground.
$C_{IN}$	Digital input capacitance.
$t_{TRANSITION}$	Delay time measured between the 50% and 90% points of the digital inputs and the switch "ON" condition when switching from one address state to another.
$t_{ON}(\overline{EN})$	Delay time between the 50% and 90% points of the $\overline{EN}$ digital input and the switch "ON" condition.
$t_{OFF}(\overline{EN})$	Delay time between the 50% and 90% points of the $\overline{EN}$ digital input and the switch "OFF" condition.
$t_{OPEN}$	"OFF" time measured between the 80% points of both switches when switching from one address state to another.
Charge Injection	A measure of the glitch impulse transferred from the digital input to the analog output during switching.
Off Isolation	A measure of unwanted signal coupling through an "OFF" switch.
Crosstalk	A measure of unwanted signal is coupled through from one channel to another as a result of parasitic capacitance.
On Response	The Frequency response of the "ON" switch.
Insertion Loss	The loss due to the ON resistance of the switch.

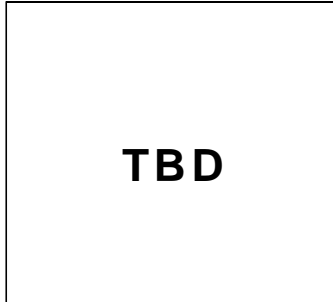
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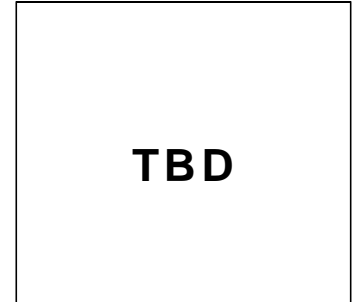
**TYPICAL PERFORMANCE CHARACTERISTICS**



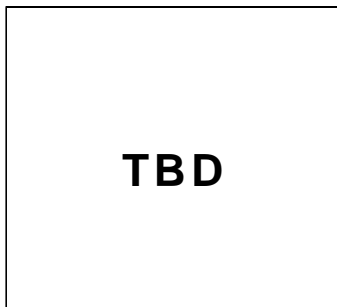
*TPC 1. On Resistance as a Function of  $V_D(V_S)$  for Single Supply*



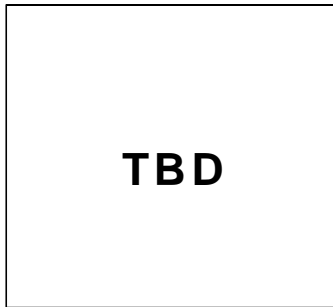
*TPC 4. On Resistance as a Function of  $V_D(V_S)$  for Different Temperatures, Single Supply*



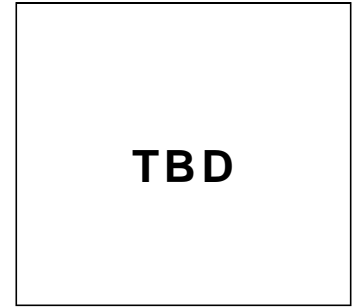
*TPC 7. Leakage Currents as a function of  $V_D(V_S)$*



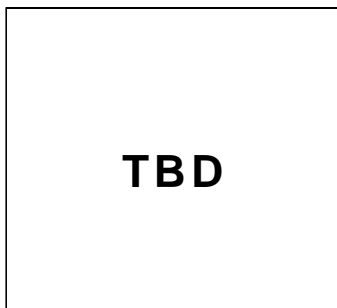
*TPC 2. On Resistance as a Function of  $V_D(V_S)$  for Dual Supply*



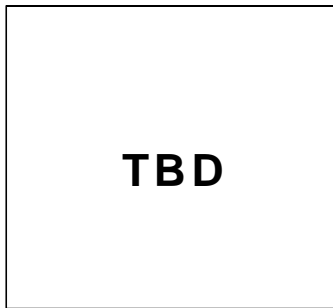
*TPC 5. On Resistance as a Function of  $V_D(V_S)$  for Different Temperatures, Dual Supply*



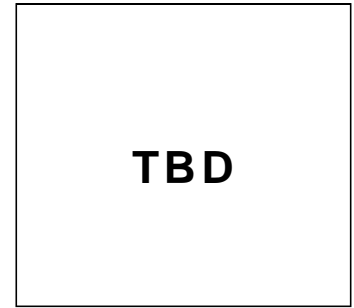
*TPC 8. Leakage Currents as a function of  $V_D(V_S)$*



*TPC 3. On Resistance as a Function of  $V_D(V_S)$  for Different Temperatures, Single Supply*



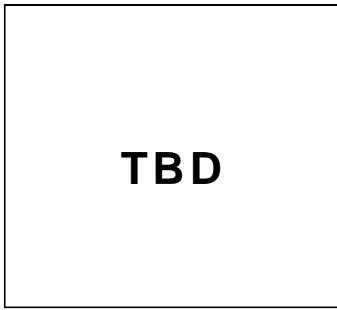
*TPC 6. Leakage Currents as a function of  $V_D(V_S)$*



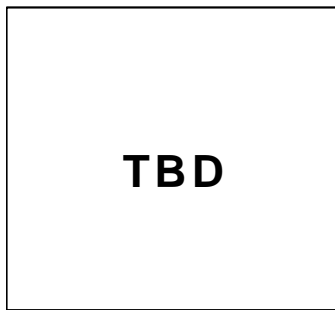
*TPC 9. Leakage Currents as a function of Temperature*

# PRELIMINARY TECHNICAL DATA

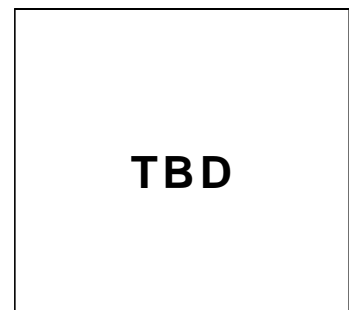
**ADG726/ADG732**



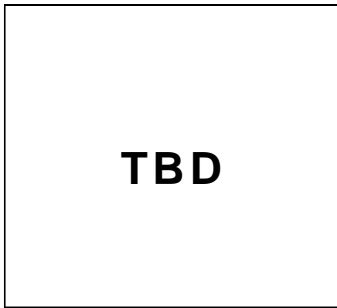
*TPC 10. Leakage Currents as a Function of Temperature*



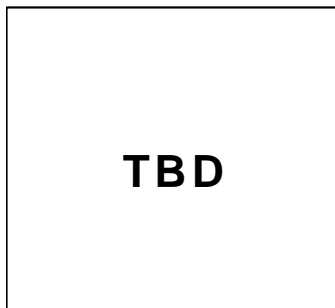
*TPC 13.  $T_{ON}/T_{OFF}$  Times vs. Temperature*



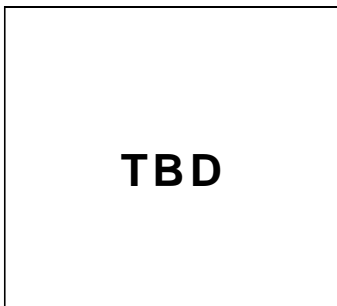
*TPC 16. On Response vs. Frequency*



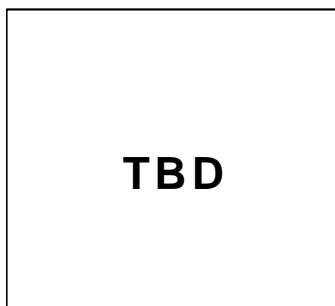
*TPC 11. Supply Currents vs. Input Switching Frequency*



*TPC 14. Off Isolation vs. Frequency*

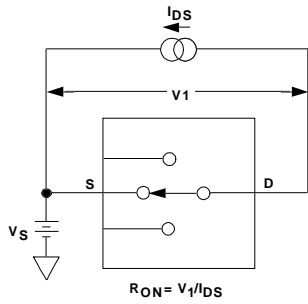


*TPC 12. Charge Injection vs. Source Voltage*

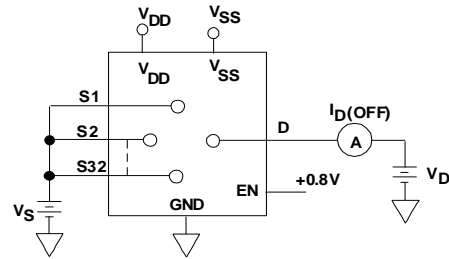


*TPC 15. Crosstalk vs. Frequency*

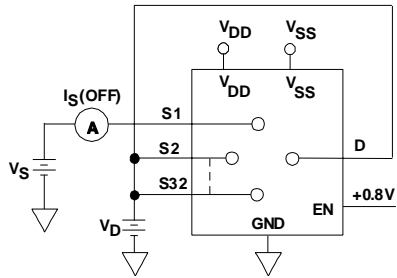
Test Circuits



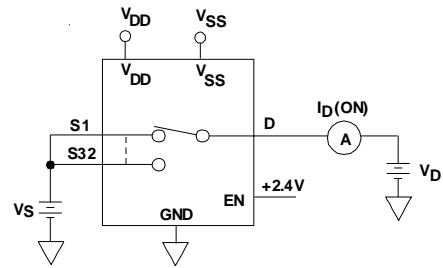
Test Circuit 1. On Resistance.



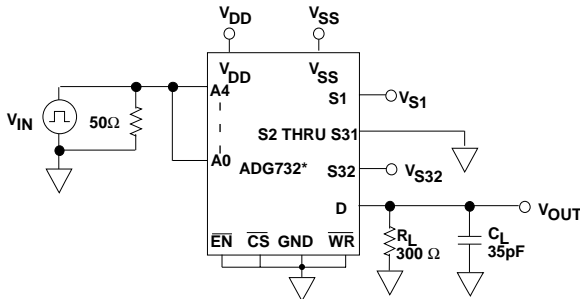
Test Circuit 3.  $I_D$  (OFF)



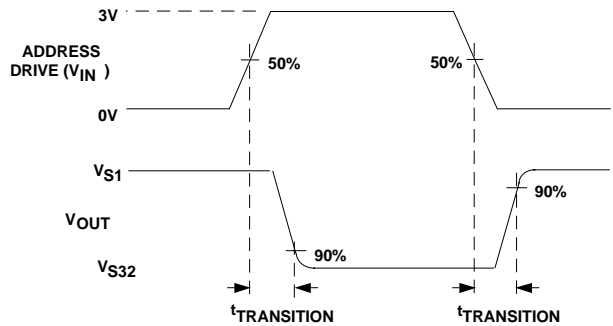
Test Circuit 2.  $I_S$  (OFF).



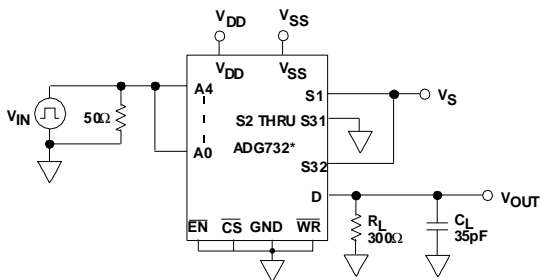
Test Circuit 4.  $I_D$  (ON)



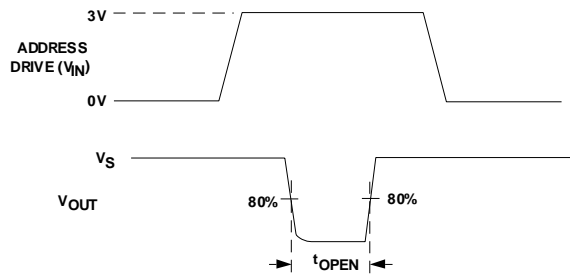
\* SIMILAR CONNECTION FOR ADG726



Test Circuit 5. Switching Time of Multiplexer,  $t_{TRANSITION}$ .



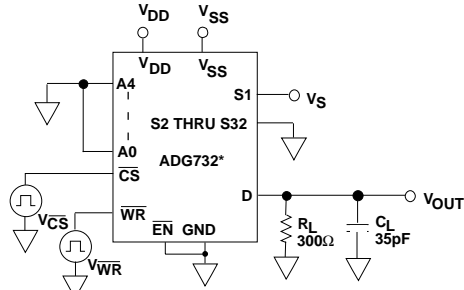
\*SIMILAR CONNECTION FOR ADG726



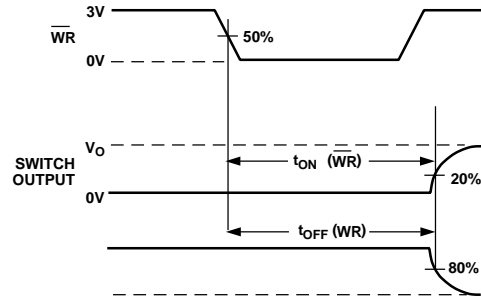
Test Circuit 6. Break Before Make Delay,  $t_{OPEN}$ .

# PRELIMINARY TECHNICAL DATA

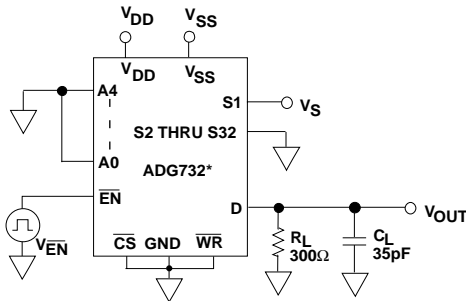
## ADG726/ADG732



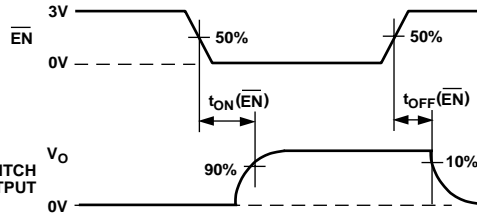
\*SIMILAR CONNECTION FOR ADG726



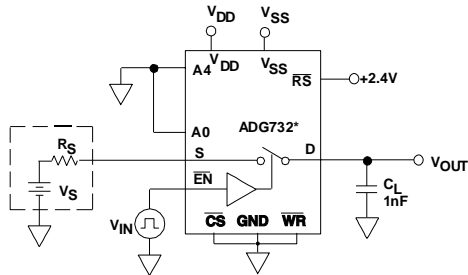
Test Circuit 7. Write Turn-On and Turn Off Time,  $t_{ON}(WR)$ ,  $t_{OFF}(WR)$ .



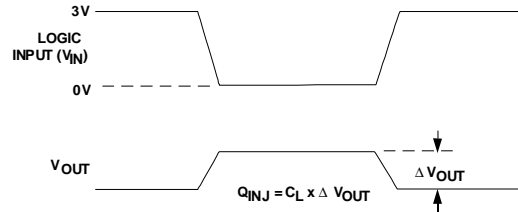
\*SIMILAR CONNECTION FOR ADG726



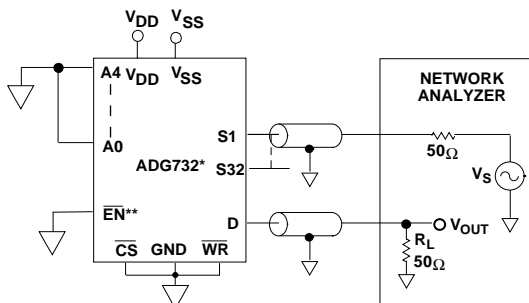
Test Circuit 8. Enable Delay,  $t_{ON}(EN)$ ,  $t_{OFF}(EN)$



\*SIMILAR CONNECTION FOR ADG726

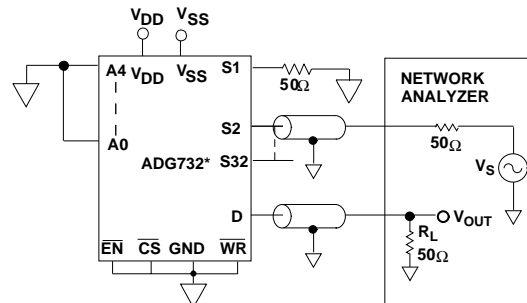


Test Circuit 9. Charge Injection.



\*SIMILAR CONNECTION FOR ADG726  
 \*\* CONNECT TO 2.4V FOR CROSSTALK MEASUREMENTS  
 $OFF\ ISOLATION = 20\ LOG_{10}(V_{OUT}/V_S)$   
 $INSERTION\ LOSS = 20\ LOG_{10}\left(\frac{V_{OUT\ WITH\ SWITCH}}{V_{OUT\ WITHOUT\ SWITCH}}\right)$

Test Circuit 10. OFF Isolation and Bandwidth.

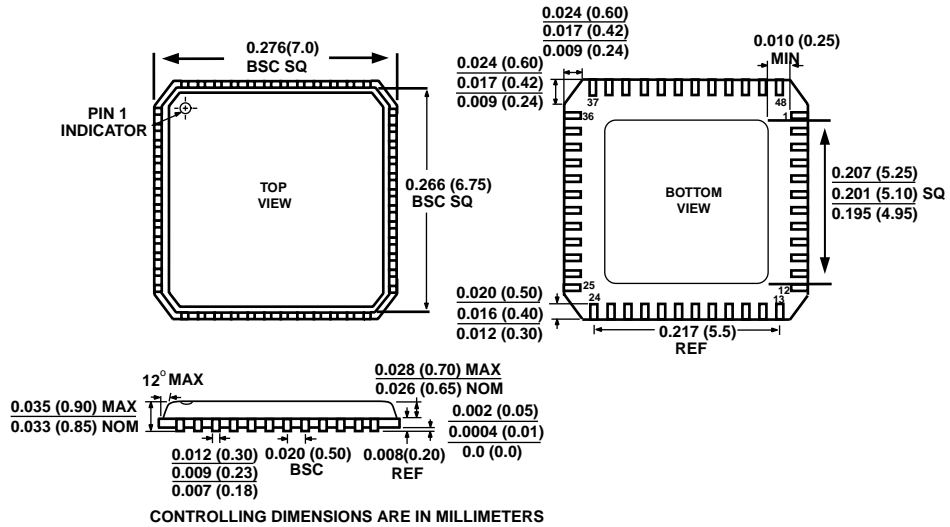


\*SIMILAR CONNECTION FOR ADG726  
 CHANNEL TO CHANNEL CROSSTALK=  
 $20\ LOG_{10}(V_{OUT}/V_S)$

Test Circuit 11. Channel-to-Channel Crosstalk.

**OUTLINE DIMENSIONS**  
Dimensions shown in inches and (mm).

**48-Lead CSP  
(CP-48)**



**48-Lead TQFP  
(SU-48)**

